

Amended

1003 is a sample, 1004 is a cantilever, 1005 is a cantilever deflection detector, 1006 is a controller, and 1007 is a computer.--

Replace the paragraph beginning at line 8 of page 1 with the following rewritten paragraph:

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--In this related art AFM, the sample 1003 is mounted on the sample stage 1002 above the XYZ translator 1001, the sample 1003 is brought into contact with a sharpened probe fixed to the tip of the cantilever 1004, and the sample is scanned in the X-Y plane by the XYZ translator 1001. During this time, deflection of the cantilever is monitored by the deflection detector 1005, the controller 1006 performs feedback control so that deflection is fixed, and the position of the sample 1003 in the Z direction is adjusted by the XYZ translator 1001. Microscopic structures on the sample surface can be observed by mapping adjustment amounts for each position on the surface of the sample onto a screen using a computer.--.

IN THE CLAIMS:

Kindly amend claims 1-17 by rewriting them in amended form as follows: